

STD38NH02L STD38NH02L-1

N-channel 24V - 0.011Ω - 38A - DPAK/IPAK STripFET™ III Power MOSFET

General features

| Туре | V _{DSS} | R _{DS(on)} | I _D |
|--------------|------------------|---------------------|----------------|
| STD38NH02L-1 | 24V | <0.0135Ω | 38A |
| STD38NH02L | 24V | <0.0135Ω | 38A |

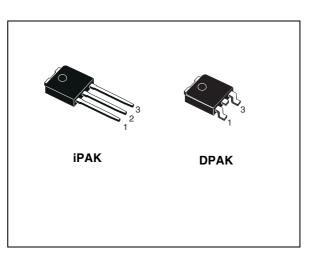
- Logic level device
- R_{DS(ON)} * Q_g Industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold drive

Description

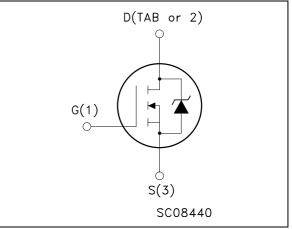
This device utilizes the latest advanced design rules of ST's proprietary STripFET[™] technology. This is suitable fot the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

Switching application



Internal schematic diagram



Order codes

| Part number | Marking | Package | Packaging |
|--------------|----------|---------|-------------|
| STD38NH02L-1 | D38NH02L | IPAK | Tube |
| STD38NH02LT4 | D38NH02L | DPAK | Tape & reel |

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Electrical ratings

| Table 1. Absolute maximum rating |
|----------------------------------|
|----------------------------------|

| Symbol | Parameter | Value | Unit |
|-----------------------------------|--|-----------------|------|
| V _{spike} ⁽¹⁾ | Drain-source voltage rating | 30 | V |
| V _{DS} | Drain-source voltage ($V_{GS} = 0$) | 24 | V |
| V _{DGR} | Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$) | 24 | V |
| V _{GS} | Gate- source voltage | ± 20 V | |
| ۱ _D | Drain current (continuous) at $T_C = 25^{\circ}C$ | 38 A | |
| ۱ _D | Drain current (continuous) at $T_C = 100^{\circ}C$ | C 27 A | |
| I _{DM} ⁽²⁾ | Drain current (pulsed) | 152 A | |
| P _{tot} | Total dissipation at $T_C = 25^{\circ}C$ | 40 W | |
| | Derating Factor | 0.27 W/°C | |
| E _{AS} ⁽³⁾ | Single pulse avalanche energy | 250 | mJ |
| T _{stg} | Storage temperature | -55 to 175 °C | |
| Тj | Max. operating junction temperature | – -55 to 175 °C | |

1. Garanted when external R_g=4.7 Ω and t_f < t_{fmax}.

2. Pulse width limited by safe operating area.

3. Starting $T_j = 25 \text{ °C}$, $I_D = 19A$, $V_{DD} = 18V$

| Table Z. Thermal uala | Table | 2. | Thermal | data |
|-----------------------|-------|----|---------|------|
|-----------------------|-------|----|---------|------|

| Rthj-case | Thermal resistance junction-case max3.75 | | °C/W |
|-----------|--|-----|------|
| Rthj-amb | Thermal resistance junction-ambient max | 100 | °C/W |
| TJ | Maximum lead temperature for soldering purpose | 275 | °C |

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

| Symbol | Parameter Test conditions | | Min. | Тур. | Max. | Unit |
|----------------------|--|---|------|----------------|-----------------|----------|
| V _{(BR)DSS} | Drain-source breakdown voltage | I _D = 25mA, V _{GS} =0 | 24 | | | V |
| I _{DSS} | Zero gate voltage drain current (V _{GS} = 0) | $V_{DS} = 20V$ $V_{DS} = 20V$, $T_{C} = 125^{\circ}C$ | | | 1 10 | μΑ μΑ |
| I _{GSS} | Gate-body leakage current ($V_{DS} = 0$) $V_{GS} = \pm 20V$ | | | | ±100 | nA |
| V _{GS(th)} | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250 \mu A$ | 1 | 1.8 | 2.5 | V |
| R _{DS(on)} | Static drain-source on resistance | $V_{GS} = 10V, I_D = 19A$ $V_{GS} = 5V, I_D = 9.5A$ | | 0.011 0.015 | 0.0135 0.025 | Ω Ω |

Table 3. On/off states

Table 4. Dynamic

| <u> </u> | | | | _ | | |
|---|--|--|------|---------------------|------|----------------------|
| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
| 9 _{fs} ⁽¹⁾ | Forward transconductance | V _{DS} = 10V _, I _D = 19A | | 19 | | S |
| C _{iss} C _{oss} C _{rss} | Input capacitance Output capacitance Reverse transfer capacitance | V _{DS} = 25V, f = 1MHz, V _{GS} = 0 | | 1070 305 45 | | pF pF pF |
| R _G | Gate Input Resistance | f = 1 MHz Gate DC Bias = 0 Test Signal Level = 20 mV Open Drain | | 1 | | Ω |
| t _{d(on)} t _r t _{d(off)} t _f | Turn-on delay time Rise time Turn-off delay time Fall time | $V_{DD} = 10V, I_D = 19A$ $R_G = 4.7\Omega V_{GS} = 10V$ (see <i>Figure 13</i>) | | 7 62 25 12 | | ns ns ns ns |
| Q _g Q _{gs} Q _{gd} | Total gate charge Gate-source charge Gate-drain charge | $\begin{array}{l} 0.44V \leq \!$ | | 18 4 2.5 | 24 | nC nC nC |
| Q _{oss} ⁽²⁾ | Output charge | V_{DS} = 16 V, V_{GS} = 0 V | | 6.5 | | nC |

1. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %.

2. Qoss = Coss^{*} Δ Vin , Coss = Cgd + Cds . See *Chapter 4: Appendix A*



| Symbol | Parameter | Test conditions | Min. | Тур. | Max. | Unit |
|--|--|--|------|-----------------|-----------|---------------|
| I _{SD} I _{SDM} ⁽¹⁾ | Source-drain current Source-drain current (pulsed) | | | | 38 152 | A A |
| V _{SD} ⁽²⁾ | Forward on voltage | I _{SD} = 19A, V _{GS} = 0 | | | 1.3 | V |
| t _{rr} Q _{rr} I _{RRM} | Reverse recovery time Reverse recovery charge Reverse recovery current | $I_{SD} = 38A, di/dt = 100A/\mu s,$ $V_{DD} = 18V, T_j = 150^{\circ}C$ (see <i>Figure 15</i>) | | 27 22 1.6 | | ns nC A |

Table 5.Source drain diode

1. Pulse width limited by safe operating area.

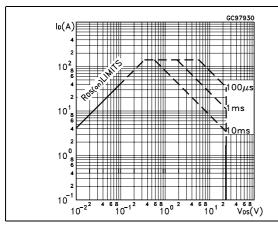
2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5 %



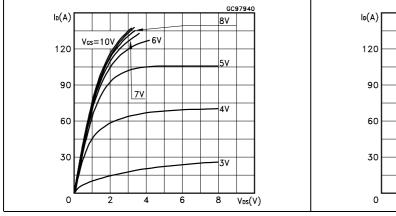
GC94760

Electrical characteristics (curves) 2.1

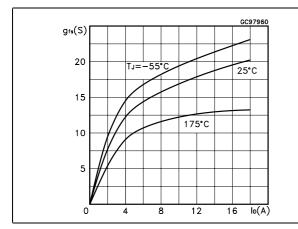
Figure 1. Safe operating area













280DPE

d = 0.5

к

10

Thermal impedance

Figure 2.

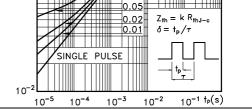


Figure 4. **Transfer characteristics**

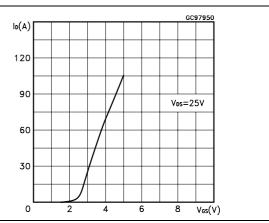
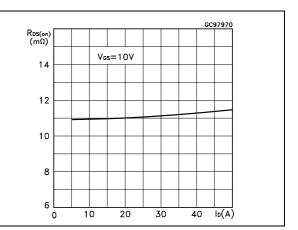


Figure 6. Static drain-source on resistance



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Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

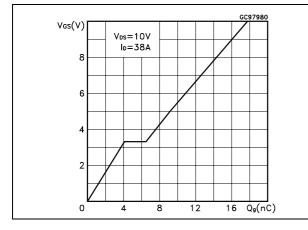


Figure 9. Normalized gate threshold voltage vs temperature

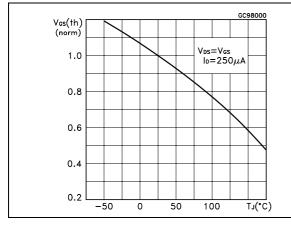


Figure 11. Source-drain diode forward characteristics

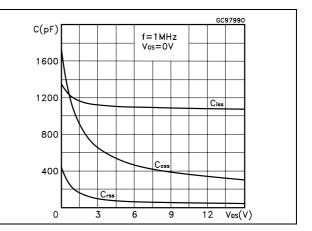


Figure 10. Normalized on resistance vs temperature

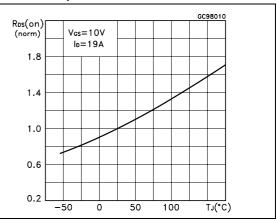
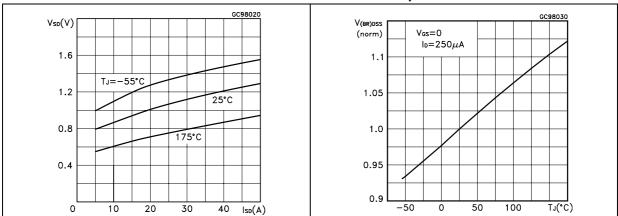


Figure 12. Normalized breakdown voltage vs temperature



3 Test circuit

Figure 13. Switching times test circuit for resistive load

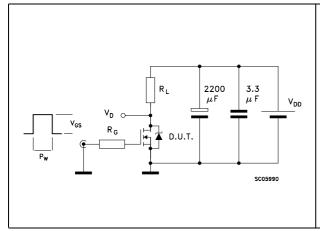
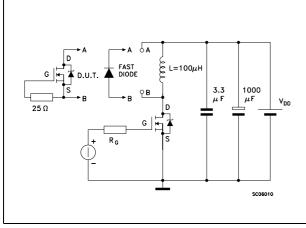


Figure 15. Test circuit for inductive load switching and diode recovery times





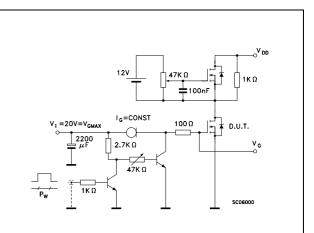
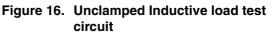


Figure 14. Gate charge test circuit



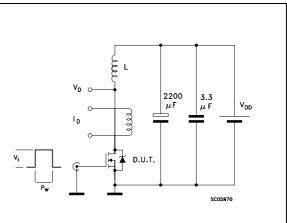
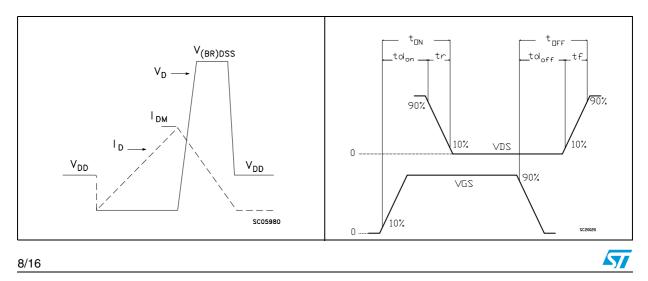
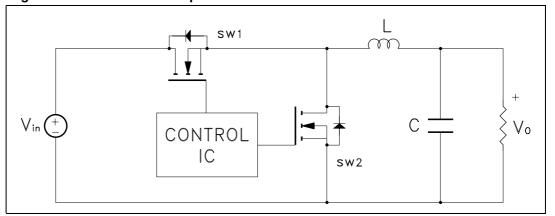


Figure 18. Switching time waveform



4 Appendix A





The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

- The low side (SW2) device requires:
- Very low R_{DS(on)} to reduce conduction losses
- Small Qgls to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;
- The high side (SW1) device requires:
- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses
- Low R_{DS(on)} to reduce the conduction losses.



| | | High side switching (SW1) | Low side switch (SW2) |
|------------------------|-----------------|--|--|
| Pconduction | | $R_{DS(on)SW1} * I_L^2 * \delta$ | $R_{DS(on)SW2} * I_L^2 * (1 - \delta)$ |
| Pswit | ching | $V_{in} * (Q_{gsth(SW1)} + Q_{gd(SW1)}) * f * \frac{I_L}{I_g}$ | Zero Voltage Switching |
| Pdiode | Recovery (1) | Not applicable | $V_{in} * Q_{rr(SW2)} * f$ |
| Fulde | Conductio n | Not applicable | $V_{f(SW2)} * I_L * t_{deadtime} * f$ |
| Pgate(Q _G) | | $Q_{g(SW1)} * V_{gg} * f$ | $Q_{gls(\mathrm{SW2})} * V_{gg} * f$ |
| P _{Qoss} | | $\frac{V_{in} * Q_{oss(SW1)} * f}{2}$ | $\frac{V_{in} * Q_{oss(SW2)} * f}{2}$ |

 Table 6.
 Power losses calculation

1. Dissipated by SW1 during turn-on

| Table 7. | Paramiters meaning |
|----------|--------------------|
|----------|--------------------|

| Parameter | Meaning | | | |
|-------------------|--|--|--|--|
| d | Duty-cycle | | | |
| Q _{gsth} | Post threshold gate charge | | | |
| Q _{gls} | Third quadrant gate charge | | | |
| Pconduction | On state losses | | | |
| Pswitching | On-off transition losses | | | |
| Pdiode | Conduction and reverse recovery diode losses | | | |
| Pgate | Gate drive losses | | | |
| P _{Qoss} | Output capacitance losses | | | |



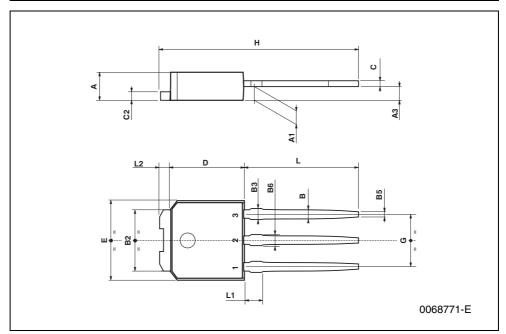
5 Package mechanical data

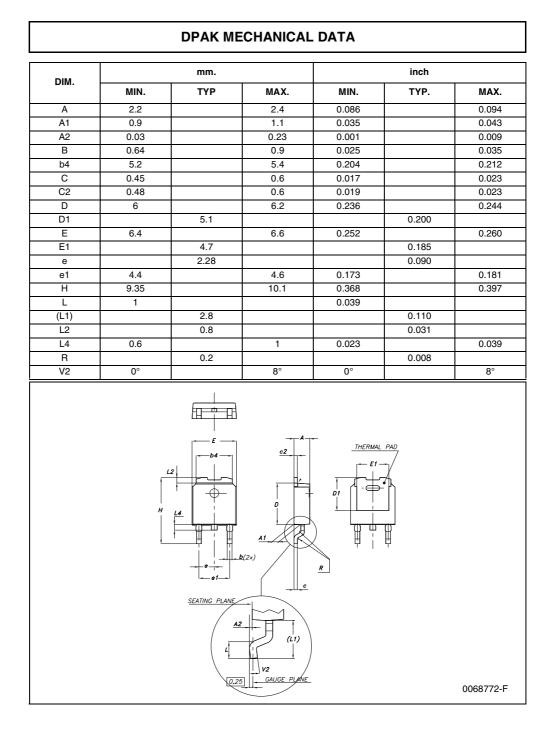
In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com



| DIM. | mm | | | inch | | |
|------|------|------|------|-------|-------|-------|
| | MIN. | TYP. | MAX. | MIN. | TYP. | MAX |
| А | 2.2 | | 2.4 | 0.086 | | 0.094 |
| A1 | 0.9 | | 1.1 | 0.035 | | 0.043 |
| A3 | 0.7 | | 1.3 | 0.027 | | 0.051 |
| В | 0.64 | | 0.9 | 0.025 | | 0.031 |
| B2 | 5.2 | | 5.4 | 0.204 | | 0.212 |
| B3 | | | 0.85 | | | 0.033 |
| B5 | | 0.3 | | | 0.012 | |
| B6 | | | 0.95 | | | 0.037 |
| С | 0.45 | | 0.6 | 0.017 | | 0.023 |
| C2 | 0.48 | | 0.6 | 0.019 | | 0.023 |
| D | 6 | | 6.2 | 0.236 | | 0.244 |
| E | 6.4 | | 6.6 | 0.252 | | 0.260 |
| G | 4.4 | | 4.6 | 0.173 | | 0.181 |
| Н | 15.9 | | 16.3 | 0.626 | | 0.641 |
| L | 9 | | 9.4 | 0.354 | | 0.370 |
| L1 | 0.8 | | 1.2 | 0.031 | | 0.047 |
| L2 | | 0.8 | 1 | | 0.031 | 0.039 |

TO-251 (IPAK) MECHANICAL DATA



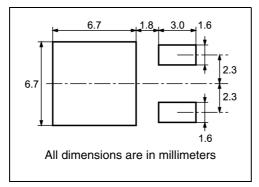


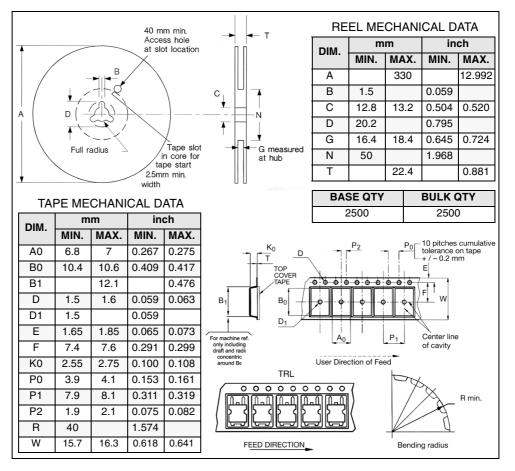


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6 Packing mechanical data

DPAK FOOTPRINT





TAPE AND REEL SHIPMENT

7 Revision history

| Table 8. | Revision | history |
|----------|----------|---------|
|----------|----------|---------|

| Date | Revision | Changes |
|-------------|----------|---------------------------------|
| 21-Jun-2004 | 7 | Preliminary version |
| 11-Jul-2006 | 8 | New template, no content change |



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